Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/695,244	CHIN ET AL.
Examiner	Art Unit
Hsien-ming Lee	2823

SEARCHED						
Class	Subclass	Date	Examiner			
438	106,110	5/31/2005	LEE			
438	113, 460		ì			
438	463,464	V.	V			

INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
EASt attached (USPAT, USPG, USOCR, EPO, JPO, IBM, Derwent)	5/31/2005	LEE		